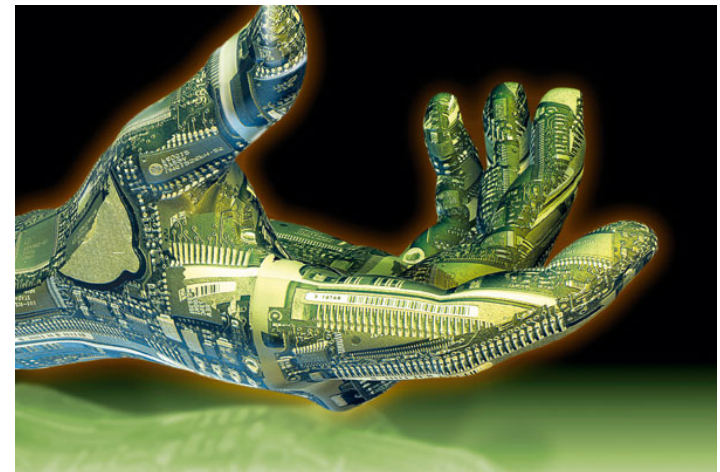


# Workload-basierte Verlässlichkeitsanalyse für eingebettete Prozessoren

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Björn Sander

Universität Tübingen /  
FZI Forschungszentrum Informatik



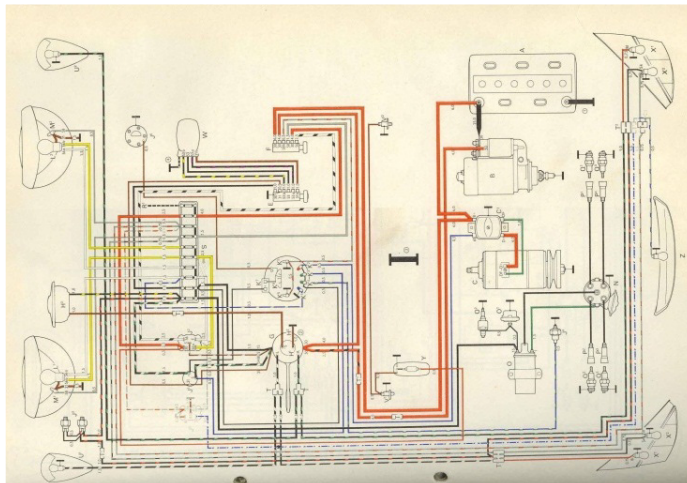
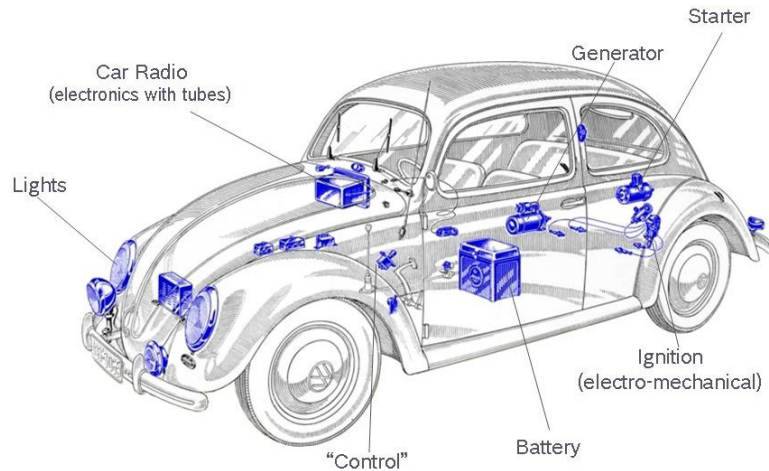
# Outline



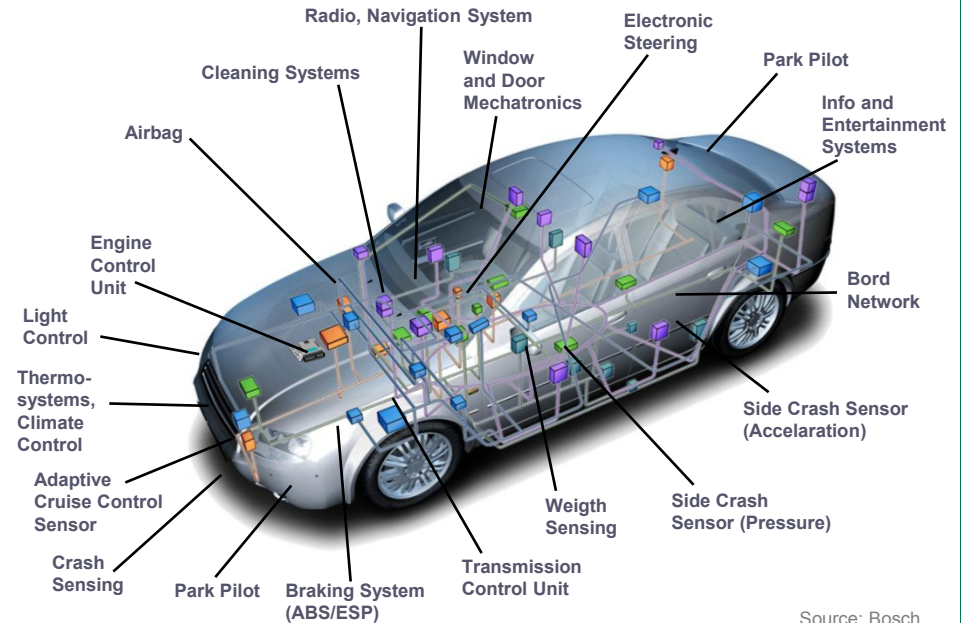
- Embedded Software: Power & Temperature
- System-Level Simulation of Non-Functional Properties by Host-Compiled Execution
- Application-Dependent Power and Temperature Simulation Framework
- Areas of Application

# Challenges: Automotive Electronics

Yesterday ...



... and today

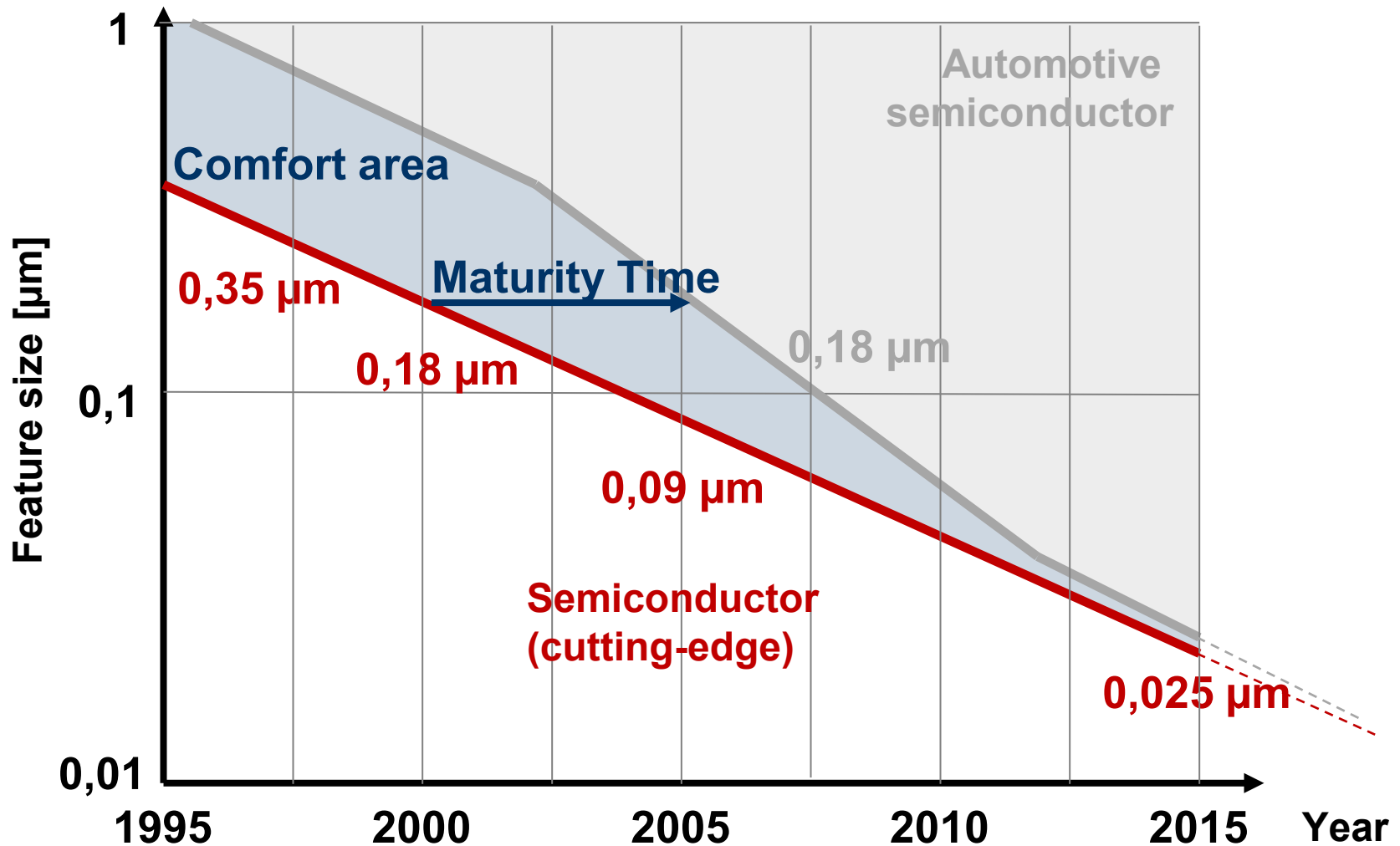


Source: Bosch

	A8	A4	A8 new
Number of ECUs	68	65	85
Number of Busses	6	6	7
Software (Mbyte)	60	90	>230

Source: Audi

# Automotive Electronics – Reducing Comfort Area



# Temperatures: Dominated by Local Power Effects

- “...thermal modeling at finer granularity level i.e., transistor level or logic gate level is required for more accurate estimation of local hot spots.”  
Bansal et al., ASP-DAC 2006

- “...hot spots tens of micrometers in

## Conclusion: Non-Functional Properties

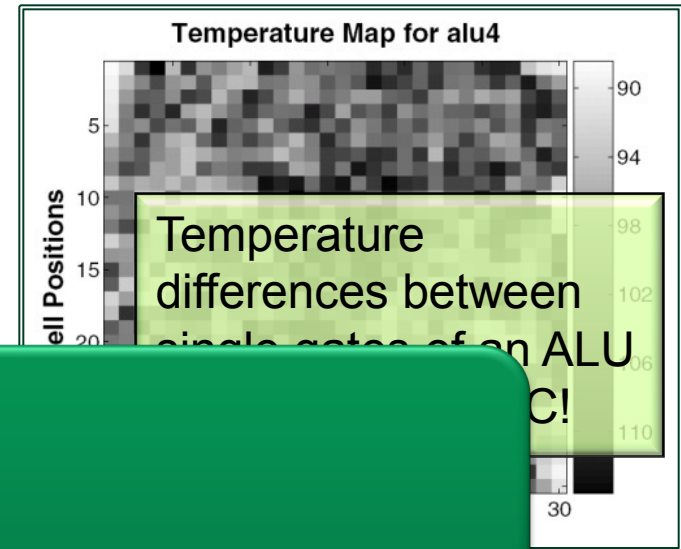
- Performance
- Energy and Power Consumption
- Temperature and Power Densities

**have to be considered and are strongly application-dependent**

- Example: ARM7TDMI

- Power RUN state: 1.3 mW =>  
Power density: 3.9 W/cm<sup>2</sup>

**Assuming an equal distribution is probably not accurate**



	Opt	90 nm
Frequency* (MHz)	115	133
Area (mm <sup>2</sup> )	0.26	0.18
Power † (mW/MHz)	0.06	0.03

\* Worst case conditions - 0.18µm process - 1.62V, 125°C, slow silicon ; 0.13µm process - 1.08V, 125°C, slow silicon ; 90nm process - 0.9V, 125°C, slow silicon  
† Typical case conditions - 0.18µm process - 1.2V, 25°C, typical silicon ; 90nm process - 1.2V, 25°C, typical silicon



# Example: Power Simulation at Different Levels of Abstraction



- ARM7TDMI, 90 nm, 236 MHz, 0.18 mm<sup>2</sup>

Accuracy insufficient. System model disregards the number of branches in the application.

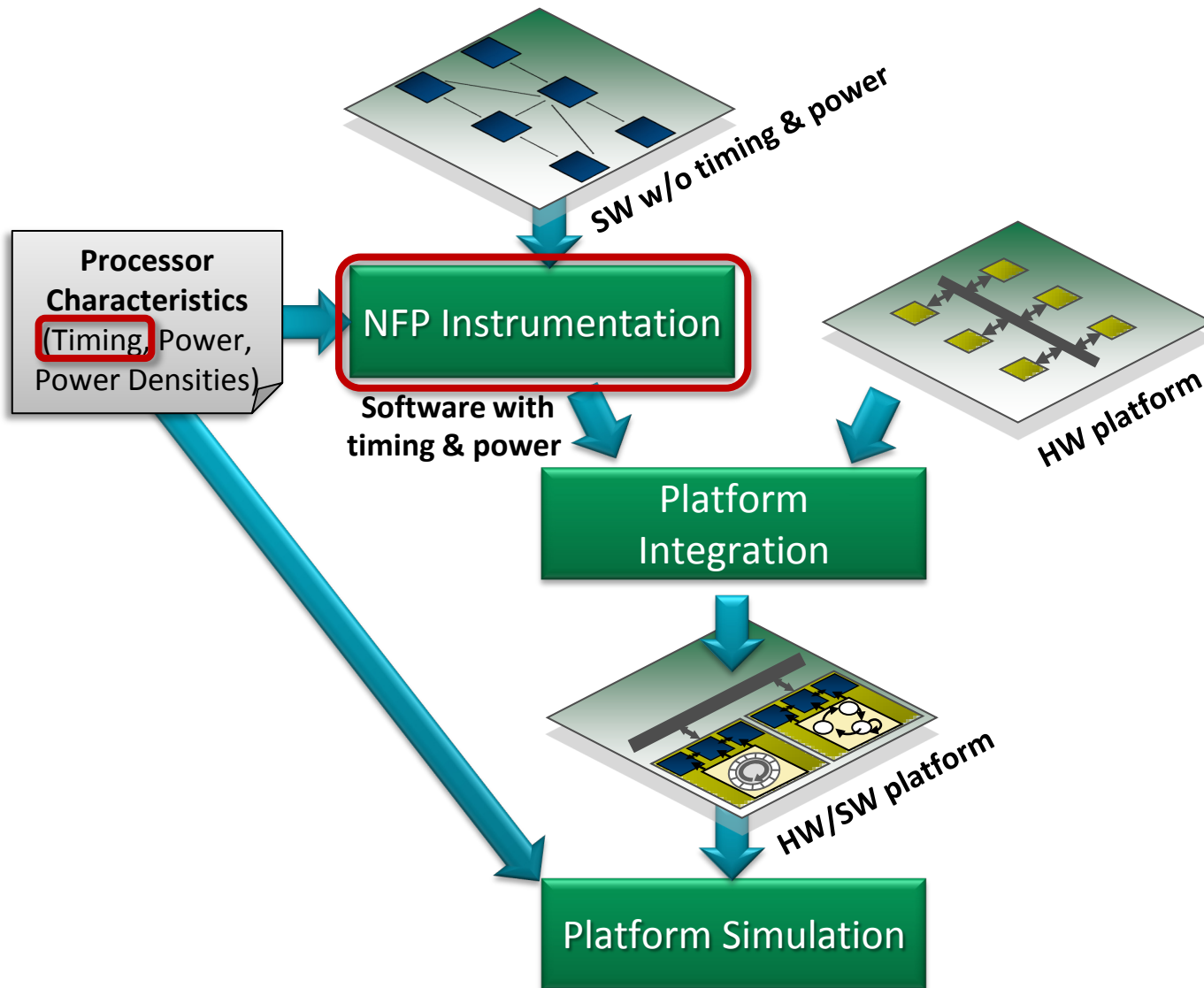
Functional Representation	Power Model	gcd		ellip	
		Simulation Factor (Simulation Time / Simulated Time)	Average Power - Error (comp. to MS+PC)	Simulation Factor	Average Power - Error
Task Graph, CDG, CFG	Average	<< 1	4.17 uW - 81 %	<< 1	4.17 uW - 541 %
Instrum. Source-Code	Instruction-Dependent	0.5	5.8 uW - 31 %	0.1	0.39 uW - 66 %
Static Binary Transl., Dynamic Binary Transl.	Data-Dependent	75	9.69 uW - 28 %	10	0.70 uW - 7 %
Netlist: ModelSim (MS) + Power Compiler (PC)	PC Internal	> 10 <sup>10</sup>	7.57 uW	> 10 <sup>10</sup>	0.65 uW

Data-dependent power model leads to a small error. But usually some kind of RTL simulation is necessary to calculate input stimuli of the components.

Simulation speed and appearing error are acceptable. Efficient link with information from binary level could be very promising.

# SYSTEM-LEVEL SIMULATION OF NON-FUNCTIONAL PROPERTIES BY HOST-COMPILED EXECUTION

# Simulation of Functional and Non-Functional Behavior – Basic Idea





# Basic Idea: Source-Level Timing Instrumentation



## Proposed Hybrid Approach

- **Compilation into binary code**
- **Static execution time analysis** w.r.t. architectural details  
**Back-annotation of analyzed timing information** into the source code
- **Simulation** by host-compiled execution

Compilation

```
int f( int a, int b,  
      int c, int d )  
{  
    int res;  
    res = (a + b) << c - d;  
    delay( 3, ms );  
}
```

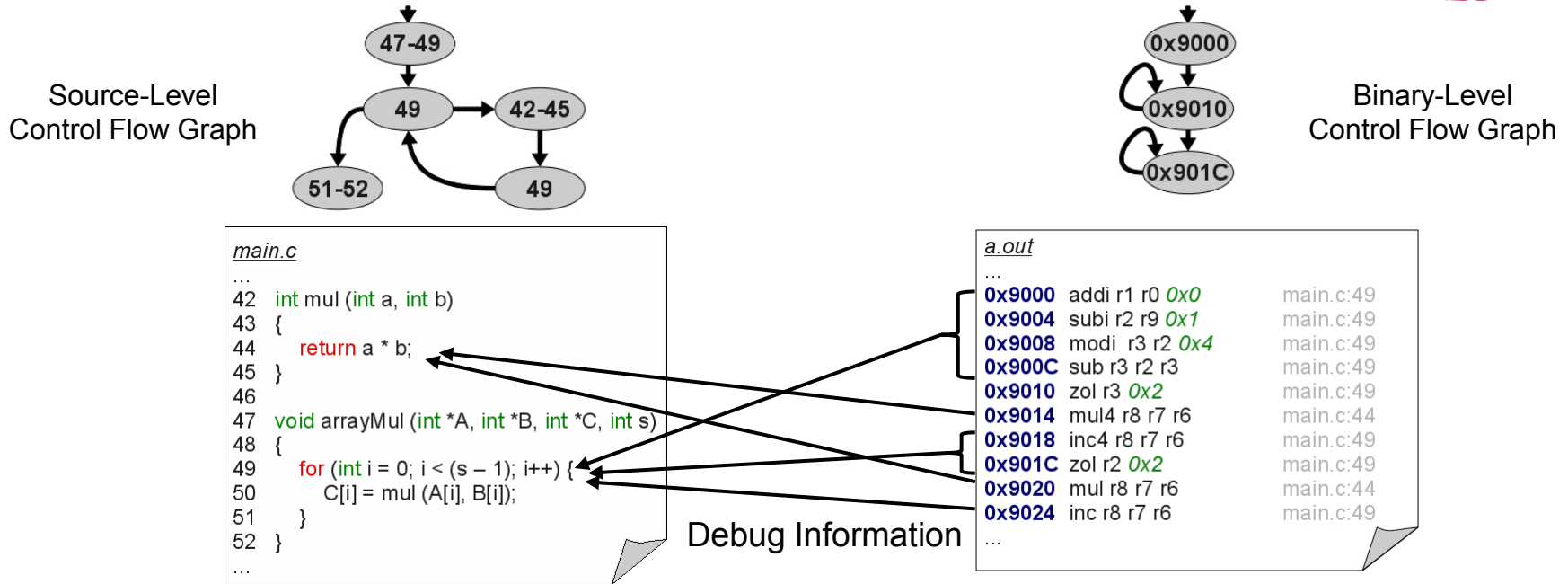
```
00000000 <f>:  
; int f( int a, int b  
;      int c,  
; {  
    3 ms
```

Back-annotation

## Important

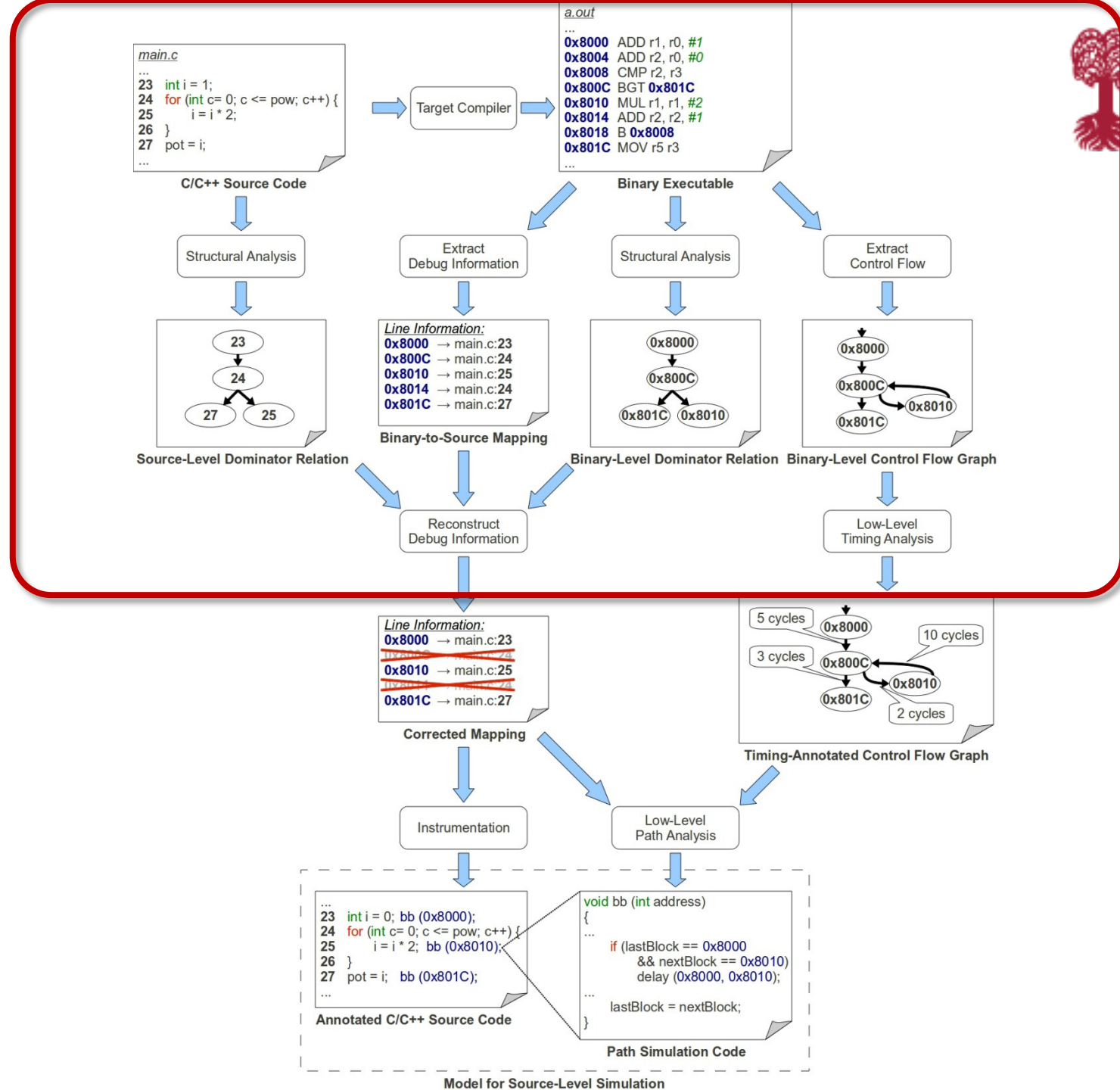
- Requires accurate relation between source code and binary code
- Run-time models for **branch prediction** and **caching** have to be incorporated

# Compiler Optimizations

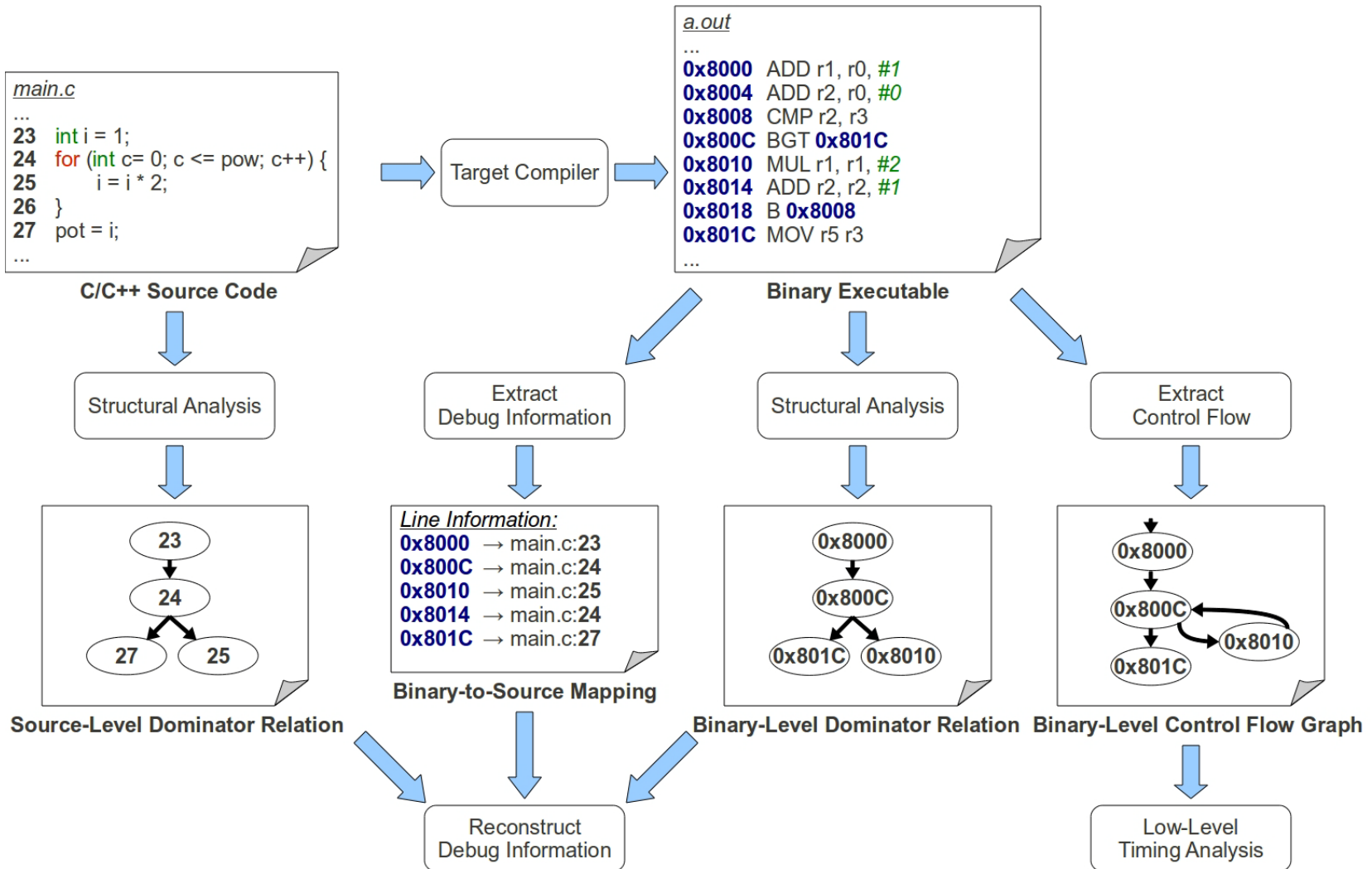


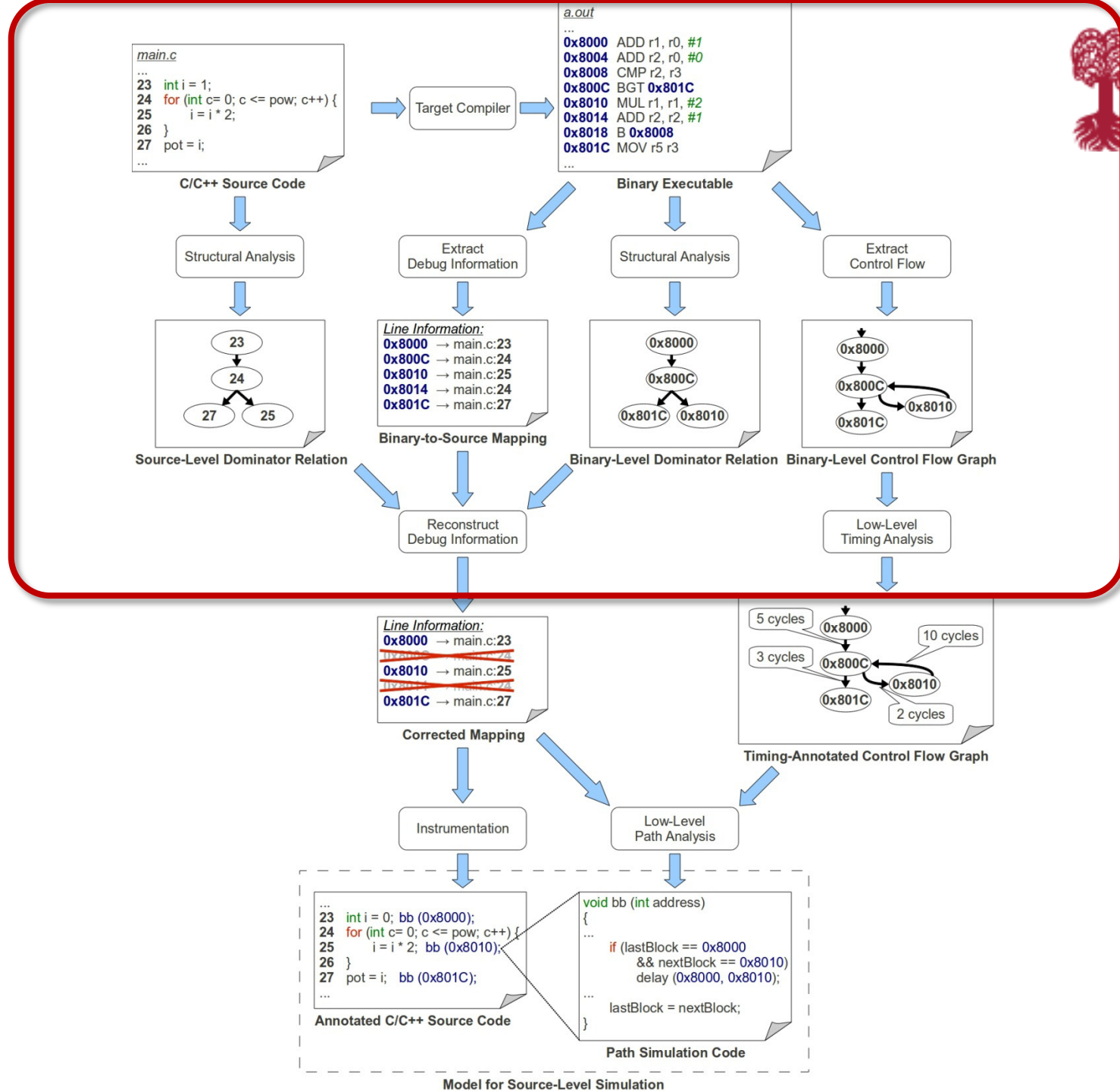
- **Structure of source code and binary code can be completely different**
  - Function Inlining adds basic blocks
  - Loop Unrolling modifies execution count of basic blocks
  - ...
- **Compilers don't generate accurate debug information for optimized code**
  - ➔ No 1:1 relation between source-level and binary-level basic blocks
  - ➔ Simply annotating delay attributes for source-level timing simulation does not work

**How to match structure of source code and machine instructions?**

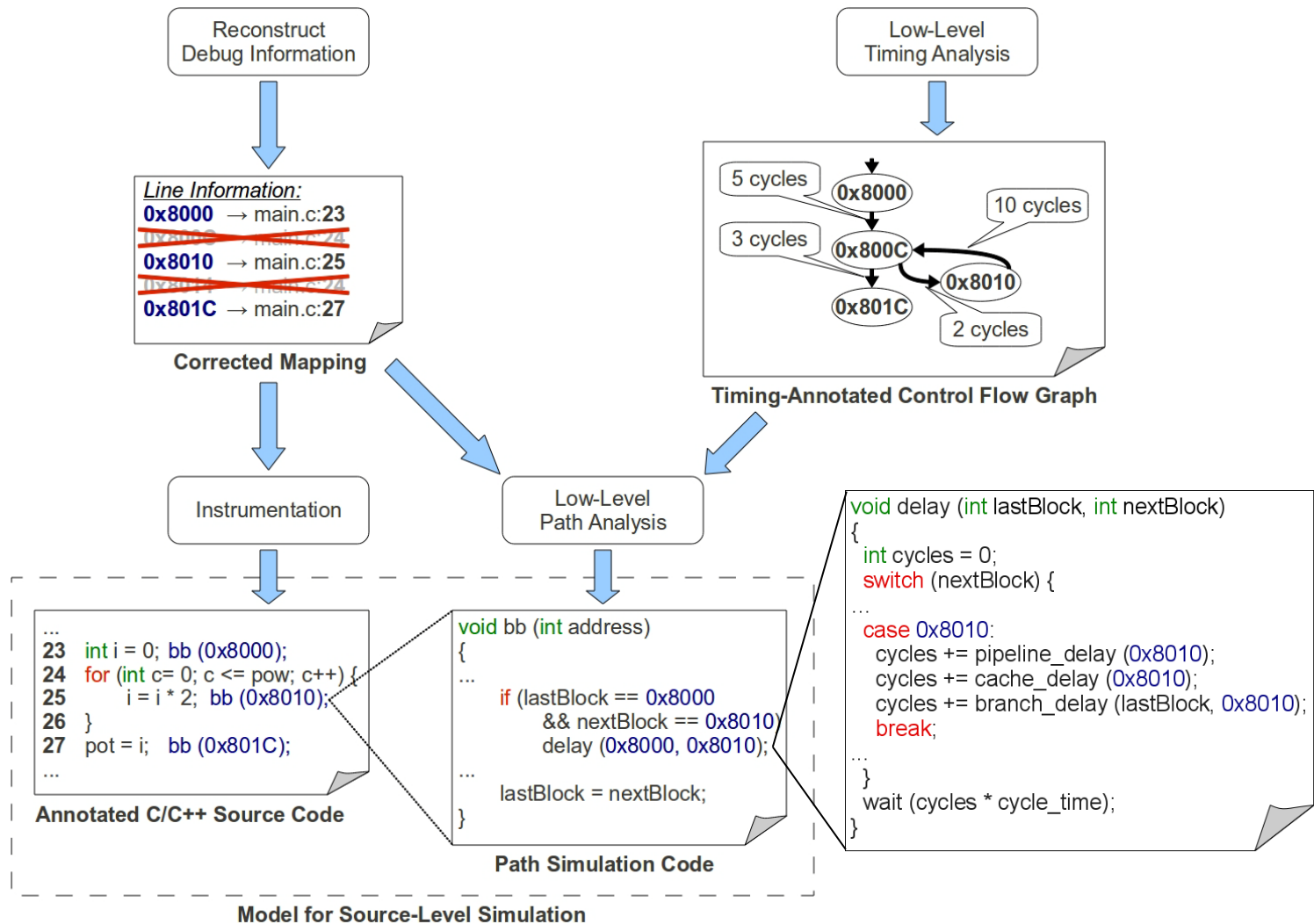


# Structural Analysis and Code Matching

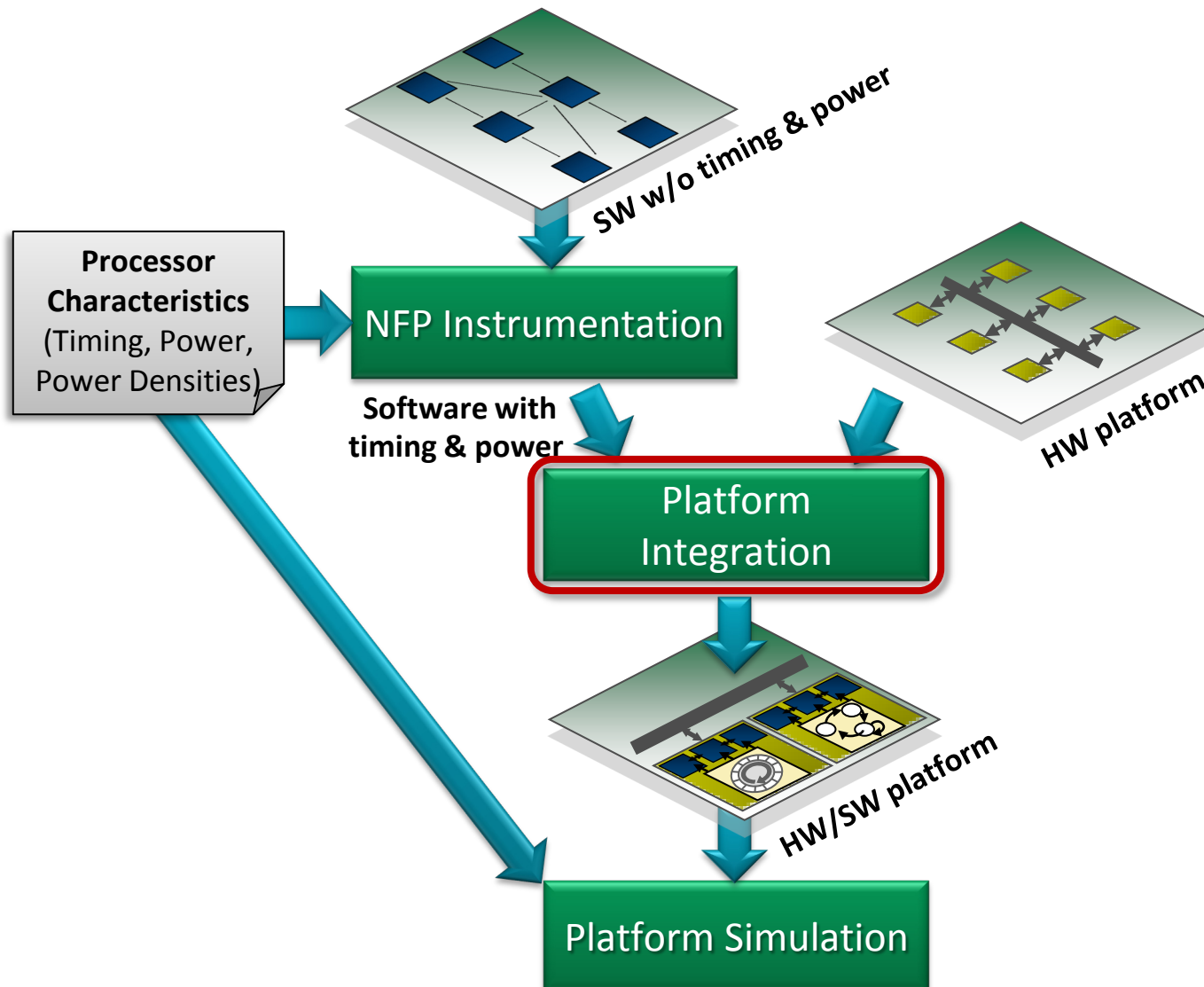




# Annotation and Path Simulation Code Generation



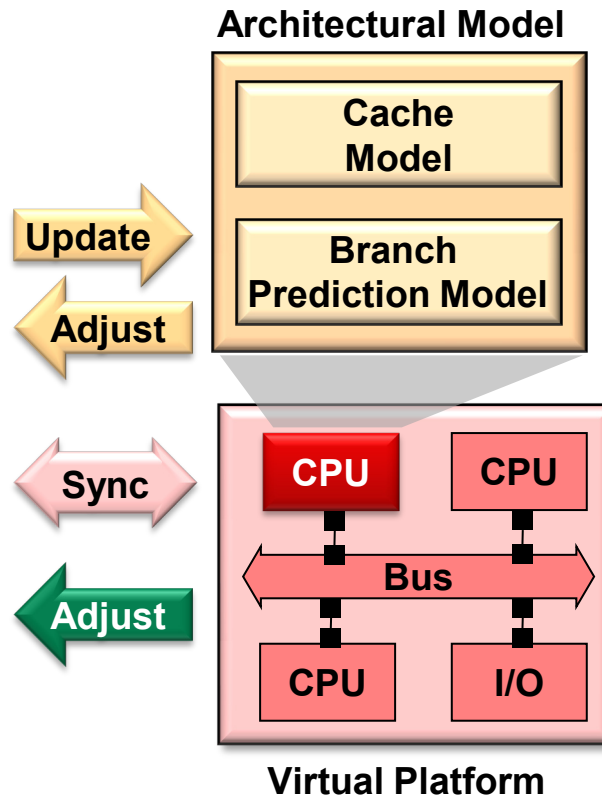
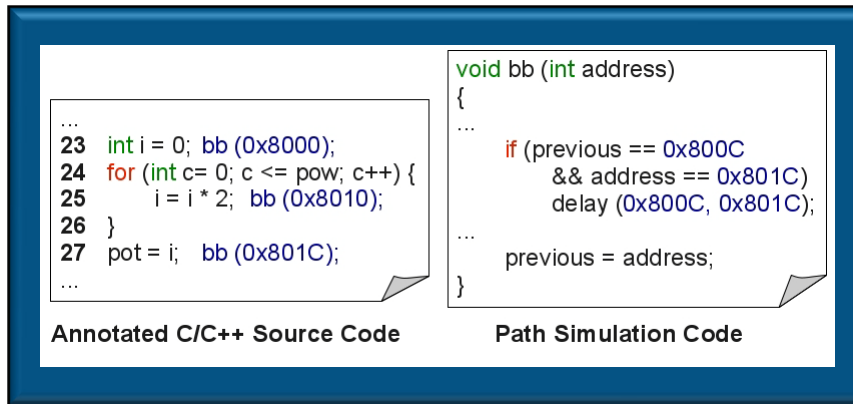
# Simulation of Functional and Non-Functional Behavior – Basic Idea





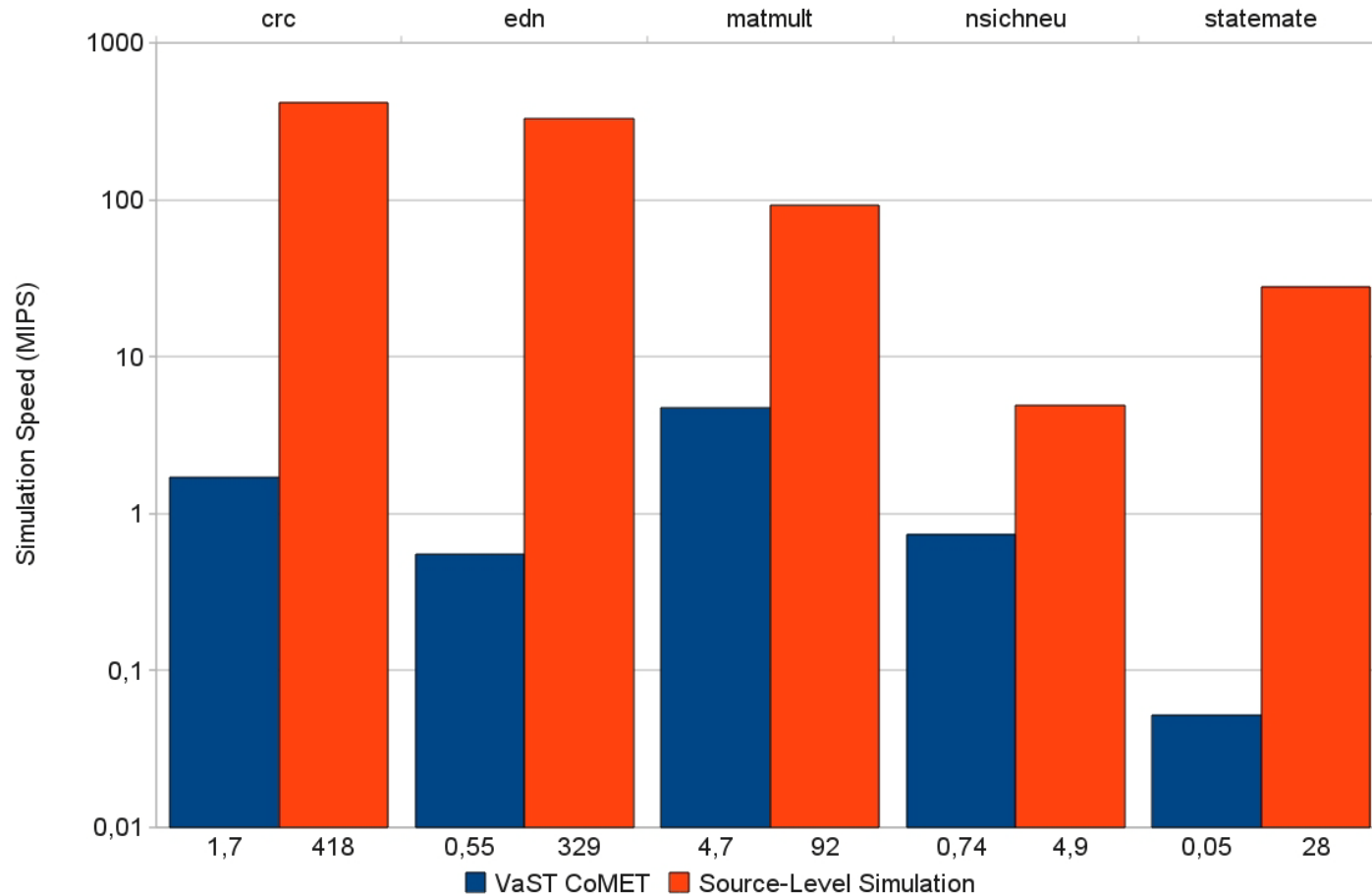
# Platform Model Integration

## Instrumented Software Module



## TLM-2.0 Loosely Timed Simulation

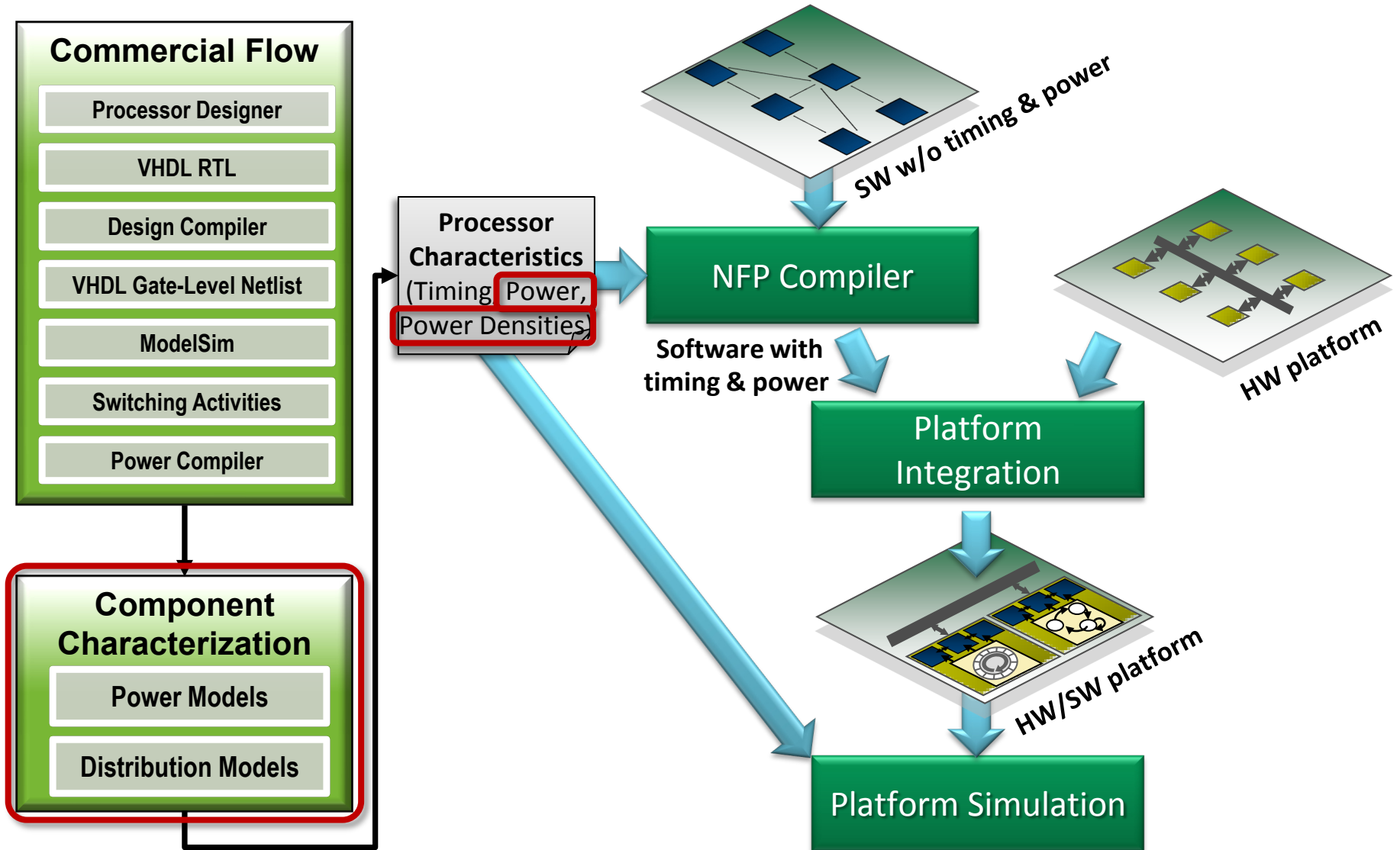
# Experimental Results



- Experiments conducted for an ARM processor
- Improved simulation performance compared to high-performance ISS based on just-in-time compilation

# APPLICATION-DEPENDENT POWER AND TEMPERATURE SIMULATION FRAMEWORK

# Power and Power Density Characterization



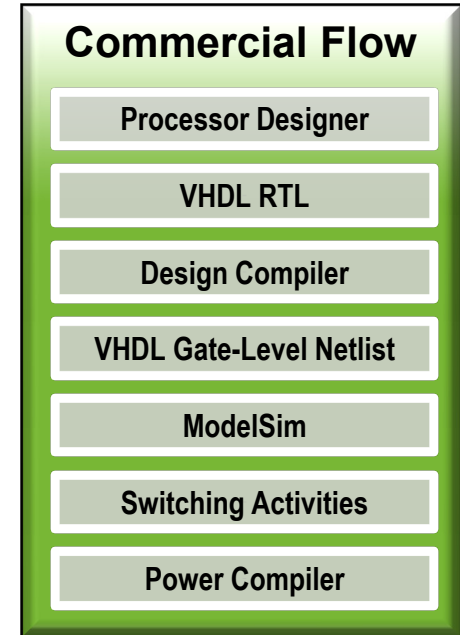
# Characterization: Power Distribution Models



## Starting Point:

- Commercial Tool Chain
- ARM-like processor design

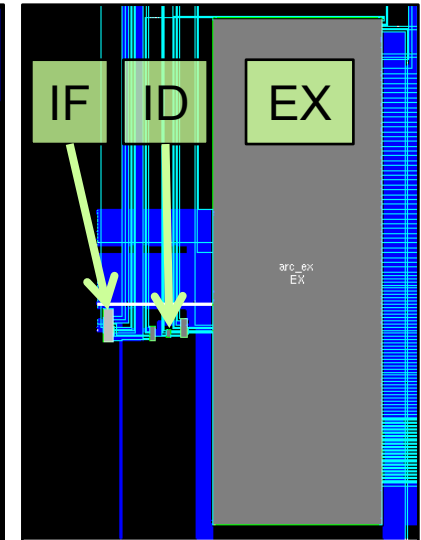
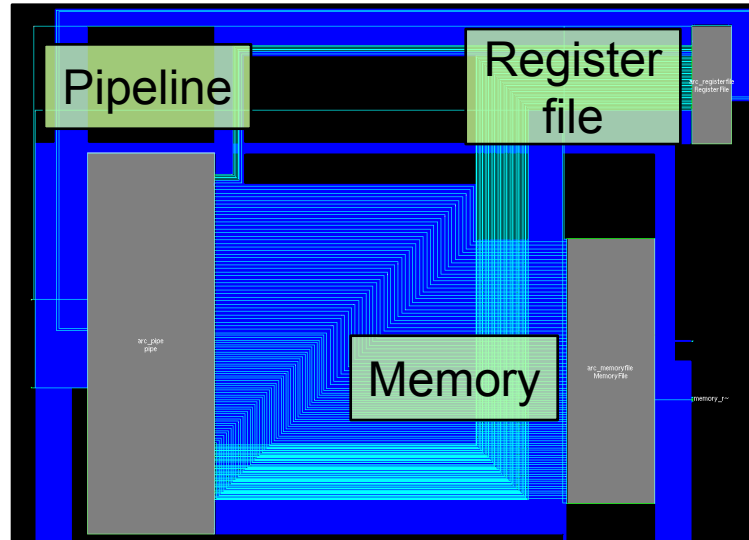
➔ Used to create accurate power measurements for processor components



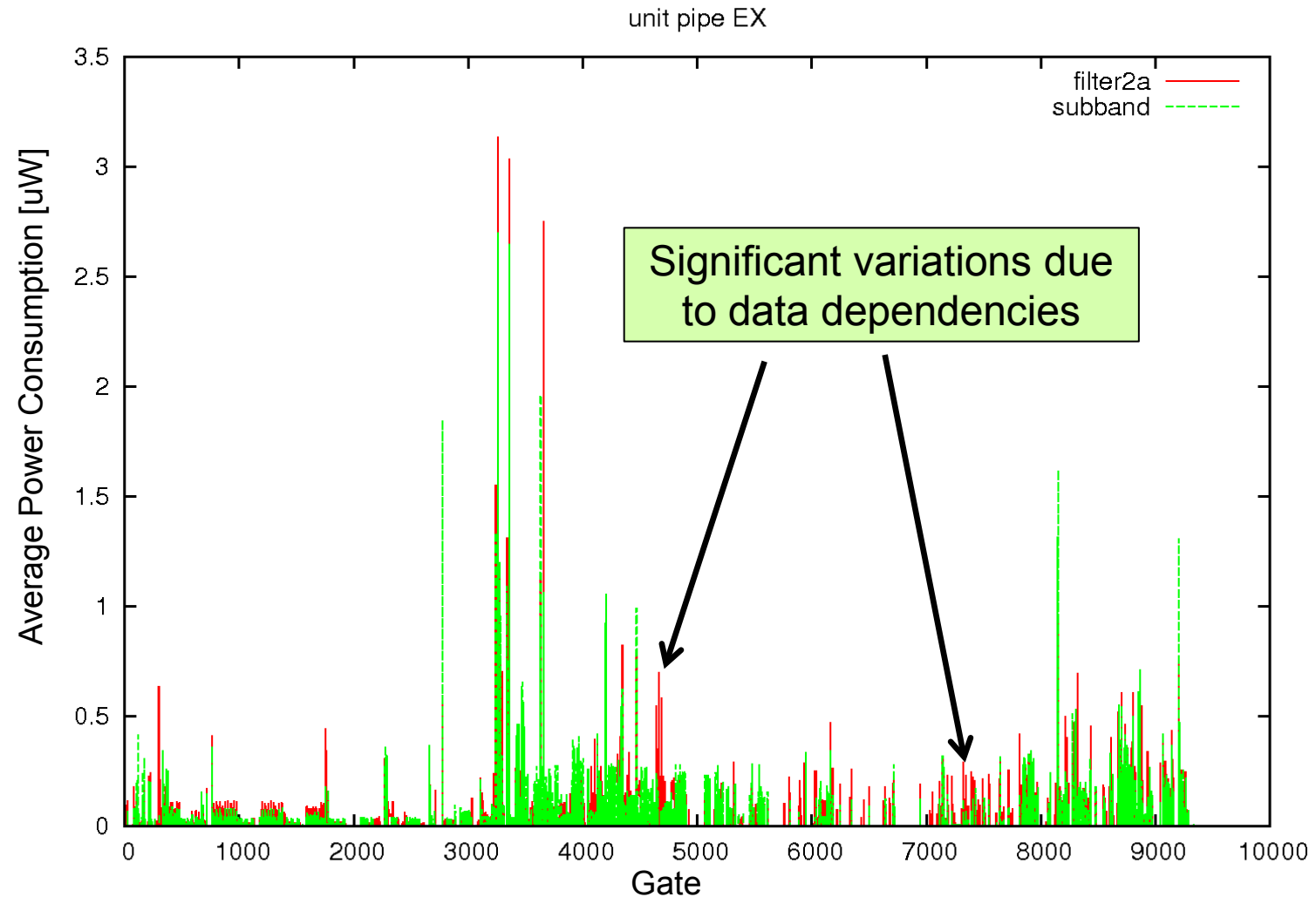
```
design_vision-t> report_cell
*****
Report : cell
Design : LT START RISC
Version : V-2004-06-SP2
Date : 2004-06-28
*****
Attributes
  h - hierarchical
  n - non-hierarchical
  u - contains unmapped logic
Cell
  arc_memoryfile MemoryFile 5461.559570
  arc_pipe pipe 31622.410156
  arc_registerfile RegisterFile 31831.921875
Total 3 cells
1
68915.882812
Log History Errors/Warnings
design_vision-t>
```

Design Compiler:

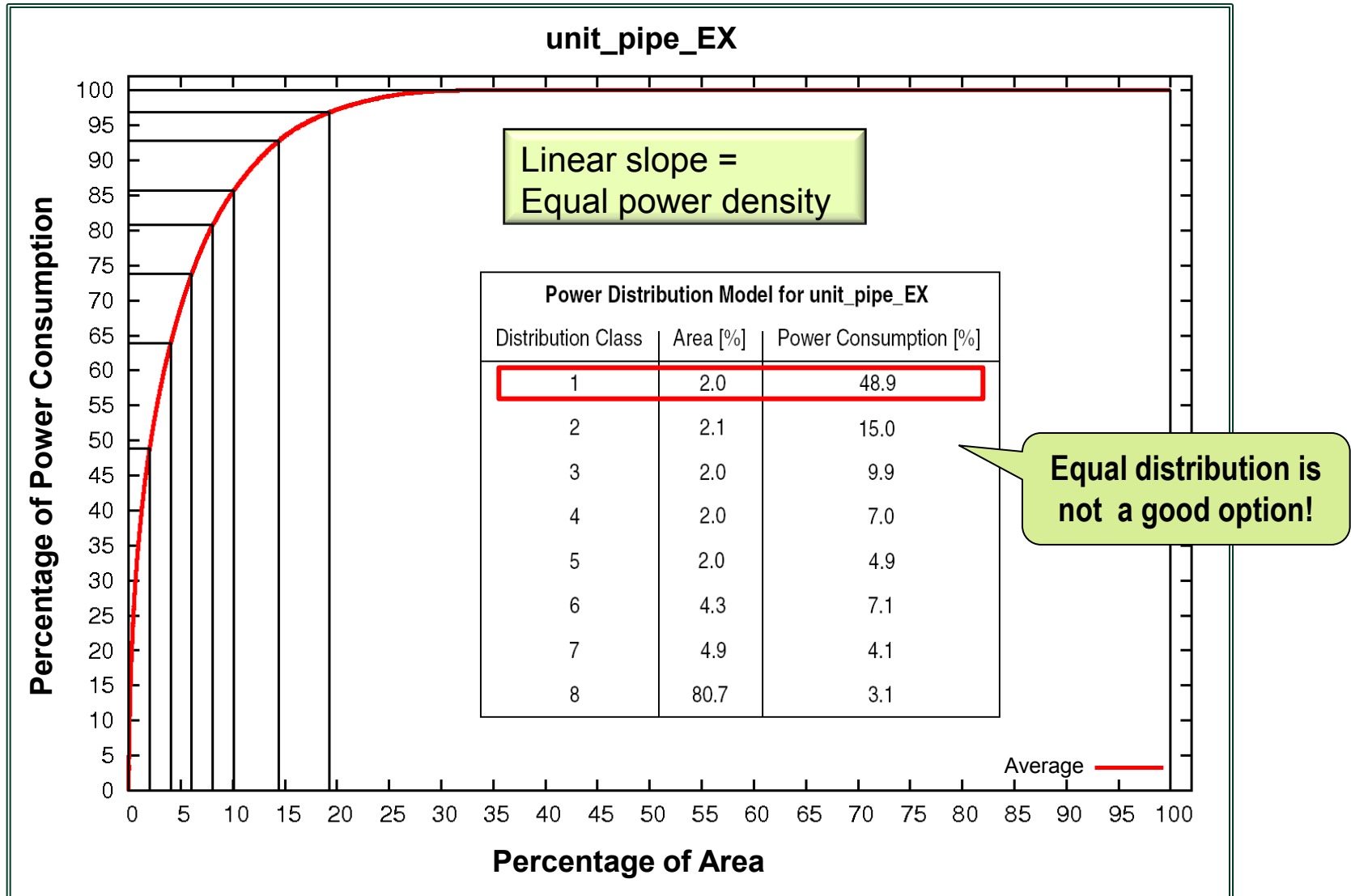
- Memory: 5461  $\mu\text{m}^2$
- Pipeline: 31622  $\mu\text{m}^2$
- Register file: 31831  $\mu\text{m}^2$



# Gate Average Power Consumption

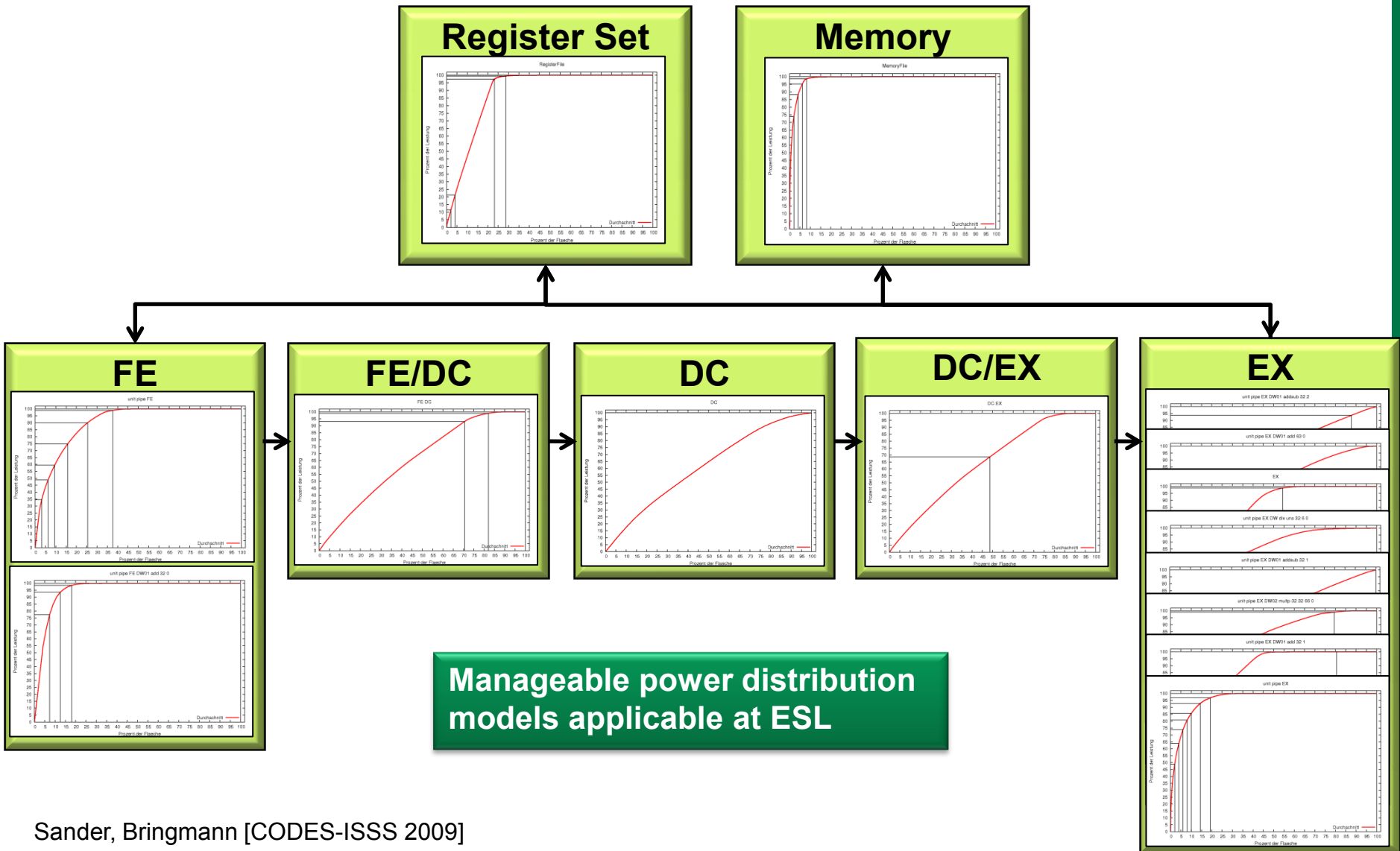


# Characterization: Power Distribution Models

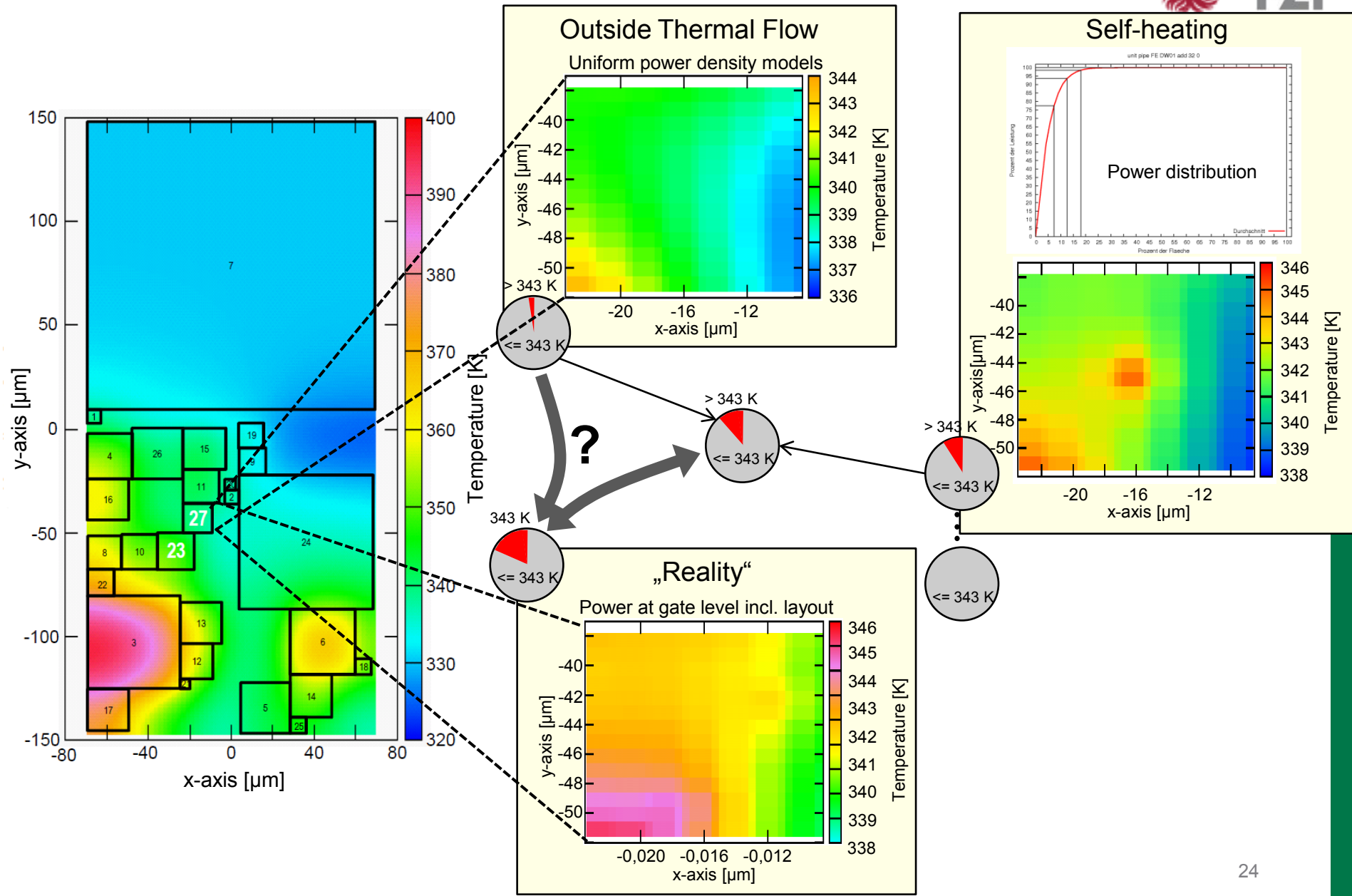




# Characterization: Power Distribution Models


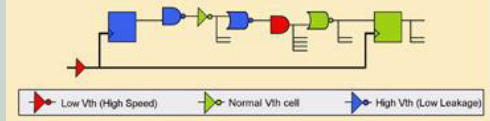

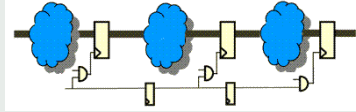






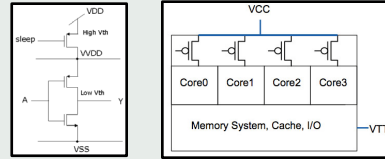



# Power Density Models for Temperature Analysis



# Low Power Design: What can be done...



Low Power Technique	Description	
<b>Multi-Voltage Threshold (MVTH)</b> 	Individual logic gates use transistors with low threshold voltages	
<b>Clock Gating (CG)</b> 	Disable registers	
<b>Operand Isolation (OI)</b> 	Datapath blocks are prevented from switching (keep inputs constant)	
<b>Multiple Supply Voltages (MSV)</b> 	Blocks operate with different supply voltages	
<b>Dynamic Voltage and Frequency Scaling (DVFS)</b> 	Adjust voltage and frequency on the fly depending on the load	
<b>Power Gating (PG)</b>  	Torn of supply voltage when not in use	
<b>Multi-Core (MC)</b> 	Distribute functionality to more than a single processor	Functionality on 2 processors $\Rightarrow f/2, 0,7*V$ $\Rightarrow$ power cut in half

For system model integration 3 different classes of low power techniques can be identified:



„Original circuit “ is changed

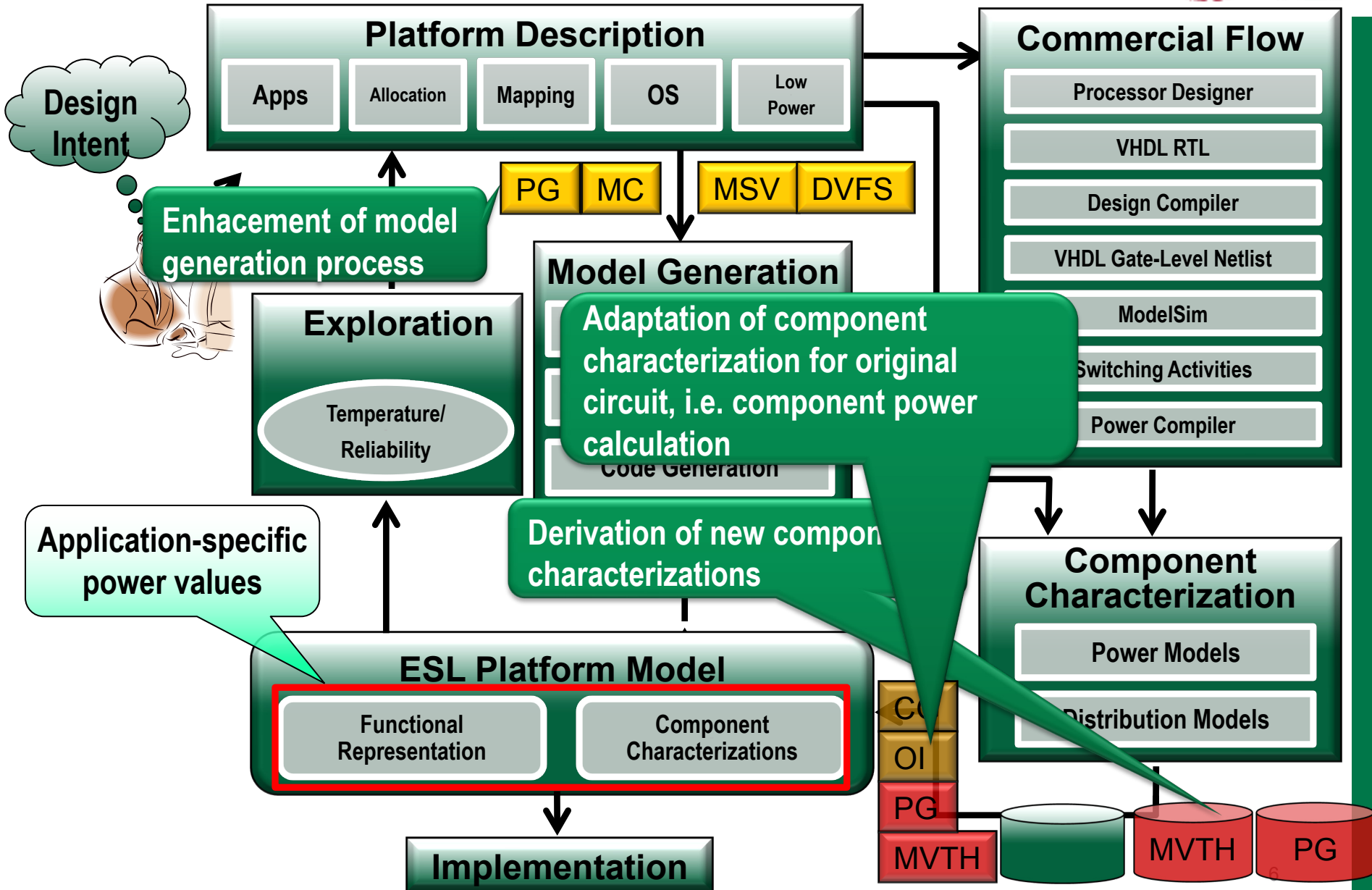


Additional hardware is used



Architectural measures

# Incorporation of Low Power Techniques



# Parameterization of the System Model



## Application

**sc\_rtos\_module** *fixed*

- fifo\_in\_port: sc\_fifo\_in<int>
- fifo\_out\_port: sc\_fifo\_out<int>
- application\_name: sc\_module\_name\*
- id: int
- reschedule\_now: sc\_event
- rtos\_context: sc\_rtos\_context\*
- run\_now: sc\_event
- scheduling\_info\_ptr: void\*

~sc\_rtos\_module()  
get\_module\_name(): sc\_module\_name\*  
notify\_reschedule(): void  
notify\_run\_now(): void  
sc\_rtos\_module()  
consume\_cpu\_cycles(): void  
increase\_cpu\_instruction\_count(): void  
read\_data(): void  
register\_task\_at\_context(): void  
write\_data(): void  
run(): void  
yield\_cpu(): void

Application-specific → generated

- sc\_rtos\_module\_adpcm
- sc\_rtos\_module\_blowfish
- sc\_rtos\_module\_jpgdecoder
- sc\_rtos\_module\_crc
- sc\_rtos\_module\_turbodecoder

~sc\_rtos\_module\_turbodecoder()  
sc\_rtos\_module\_turbodecoder()  
run(): void  
SC\_HAS\_PROCESS(): int

## Scheduling

**sc\_rtos\_scheduler** *fixed*

- runnable: vector<bool>
- running\_id: int
- scheduling\_info\_ptrs: vector<void\*>
- rtos\_context\_ptr: sc\_rtos\_context\*

~sc\_rtos\_scheduler()  
register\_task(): void  
sc\_rtos\_scheduler()  
schedule(): int  
set\_rtos\_context(): void  
task\_able\_to\_run(): void  
force\_context\_scheduling(): void

sc\_rtos\_scheduler\_round\_robin *fixed*

- running\_id\_end\_time: sc\_time
- time\_slice: sc\_time\*

~sc\_rtos\_scheduler\_round\_robin()  
sc\_rtos\_scheduler\_round\_robin()  
schedule(): int  
get\_next\_runnable\_id(): int  
SC\_HAS\_PROCESS(): int  
time\_slice\_rescheduling(): void

sc\_rtos\_scheduler\_fixed\_priority

power\_values[6] = (  
1.392\*interval\_instructions[5]+ // LDR  
1.118\*interval\_instructions[3]+ // STR  
0.595\*interval\_instructions[7]+ // STM  
1.201\*interval\_instructions[0]+ // ORR  
...  
) \* 1e-12 \* pow(voltage/0.9, 2.0)  
/ power\_interval.to\_seconds()  
+ 8.0E-9 \* area[6] \* (voltage/0.9);

print\_trace\_info(): void

## Processor

MC

**sc\_rtos\_context** *fixed*

- frequency: double
- id: int
- event\_schedule: sc\_event
- executed\_instructions: int\*
- module\_ptrs: vector<sc\_rtos\_module\*>
- next\_id: int
- running\_id: int
- scheduler\_ptr: sc\_rtos\_scheduler\*

~sc\_rtos\_context()  
force\_scheduling(): void  
get\_frequency(): double  
get\_id(): int  
increase\_instruction\_count(): void  
register\_task(): int  
sc\_rtos\_context()  
task\_able\_to\_run(): void  
get\_instruction\_count(): int  
get\_module\_ptr(): sc\_rtos\_module\*  
SC\_HAS\_PROCESS(): int  
schedule(): void

Processor-specific → generated

- sc\_rtos\_context\_power\_dvfs\_Core0
- sc\_rtos\_context\_power\_dvfs\_Core1

operation\_points: pair<double, double>\*

power\_interval: sc\_time  
power\_values: double[27]  
voltage: sc\_signal<double>

~sc\_rtos\_context\_power\_dvfs\_Core1()  
sc\_rtos\_context\_power\_dvfs\_Core1A

dvfs(): void  
power(): void  
SC\_HAS\_PROCESS(): int

CG PG  
OI MTHV

MSV

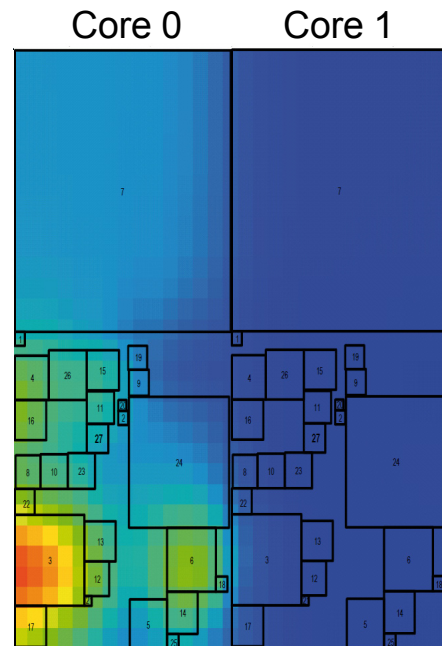
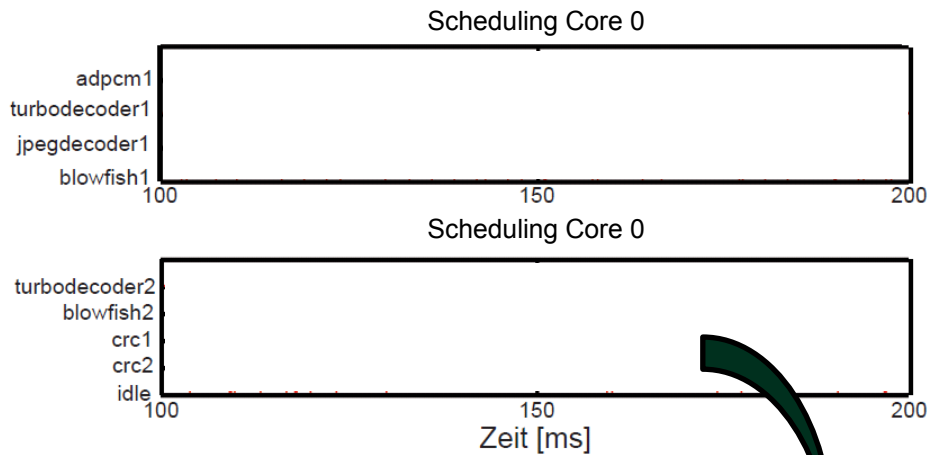
DVFS

PG

# AREAS OF APPLICATION



# Thermal Simulation

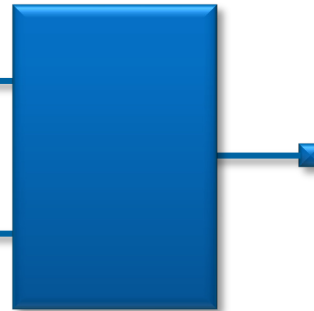
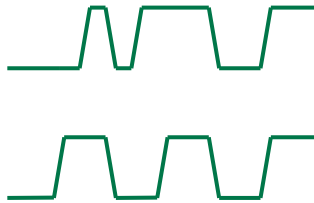
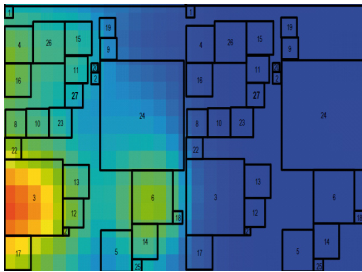


Trigger temperature-dependent robustness and reliability analyses



# Triggering of RT / Gate Level Aging Models

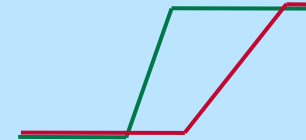
## Operating Conditions



## Modeled Effects



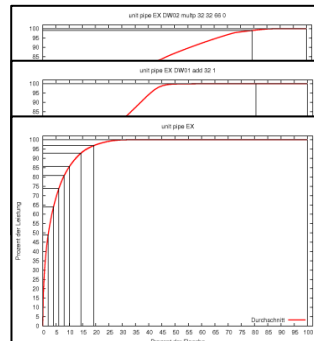
- NBTI
- HCI



## Workload

```
...  
23 int i = 0; bb (0x8000);  
24 for (int c = 0; c <= pow; c++) {  
25     i = i * 2; bb (0x8010);  
26 }  
27 pot = i; bb (0x801C);  
...
```

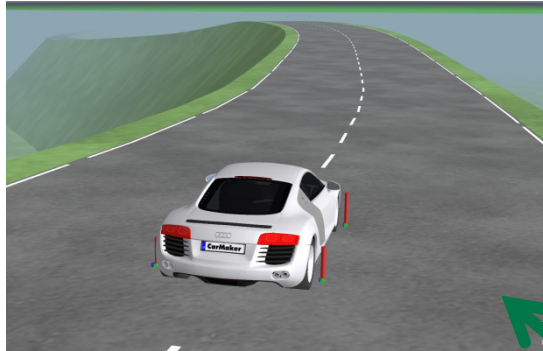
Annotated C/C++ Source Code



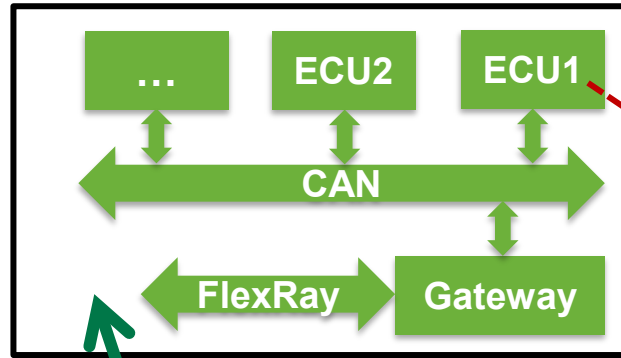
## Aged Component Model

- gate delay
  - output slope
- aged critical path

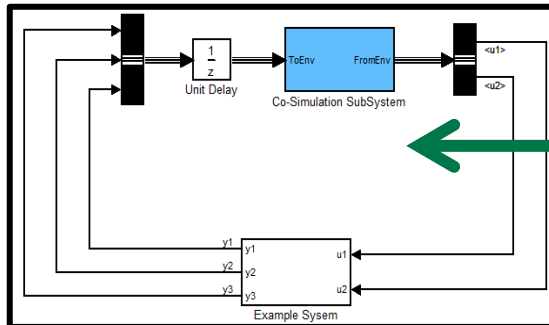
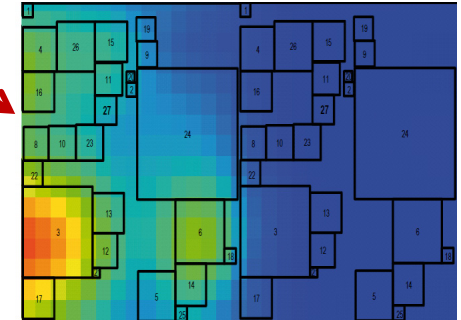
# Platform for Fast Holistic Vehicle Analysis



Dynamics Model (IPG Carmaker)

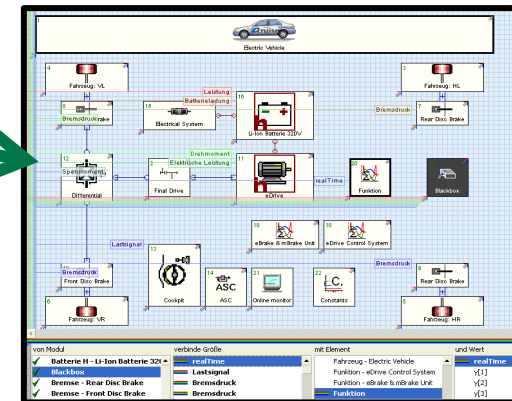


VP of the E/E Architecture



Subsystem Models (Simulink)

**Synchronized  
Simulation Kernels**



Powertrain Model (AVL Cruise)

- Fast co-simulation to cover application and environment context
- Virtual prototype (VP) reflects timing/power/temperature behavior
- Foundation for application/environment-driven robustness analysis

# Conclusion



- Non-functional properties important issue in embedded SW design
- Real-time simulation possible using source code instrumentation
  - Timing and power characteristics are annotated
  - Impact of data-dependencies and access to shared resources are solved by dynamic execution
  - Highly scalable in terms of the number of processors/processor cores
- Applicable to other non-functional properties like determination of thermal distributions and application-dependent reliability analysis
- Foundation for efficient simulation of heterogeneous HW/SW systems including sensors and actors

**Thank you very much for your attention!**

**Questions?**

**Oliver Bringmann**

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Intelligent Systems and Production Engineering (ISPE)

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